

SEMICONDUCTOR STORAGE DEVICE FORMED TO OPTIMIZE TEST TECHNIQUE AND REDUNDANCY TECHNOLOGY

CROSS-REFERENCE TO RELATED APPLICATIONS

5 This application is based upon and claims the benefit of priority from the prior Japanese Patent Application No. 2001-009370, filed January 17, 2001, the entire contents of which are incorporated herein by reference.

reference.
10 This application is a division of SN. 10/053,524, filed 1/16/02, now patent
BACKGROUND OF THE INVENTION No. 6,741,509

1. Field of the Invention

This invention relates to a semiconductor storage device and more particularly to a semiconductor storage device which is intended to optimize the test technique and redundancy technology.

2. Description of the Related Art

Recently, the storage capacity of the semiconductor storage device keeps on increasing and various test techniques for testing whether or not semiconductor storage devices are correctly operated and redundancy technologies for repairing (compensating for) defects of semiconductor storage devices come to play an important role. In the semiconductor storage device of large storage capacity, it is essential to suppress the test time for making various function tests and enhance the efficiency of the redundancy technology for repairing defects of semiconductor